Figure 1

METHOD OF DETERMINING OVERLAY TOLERANCE
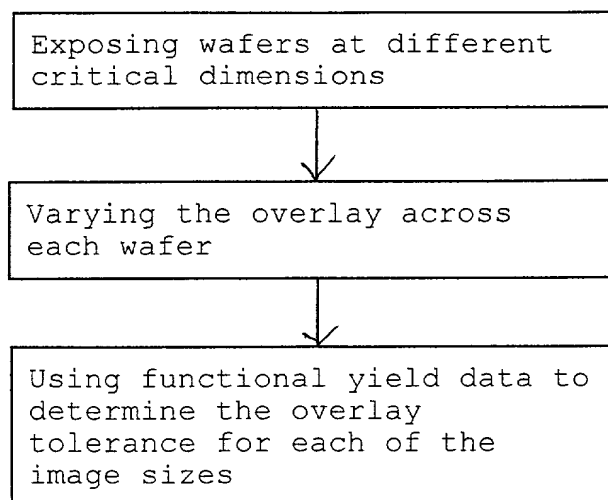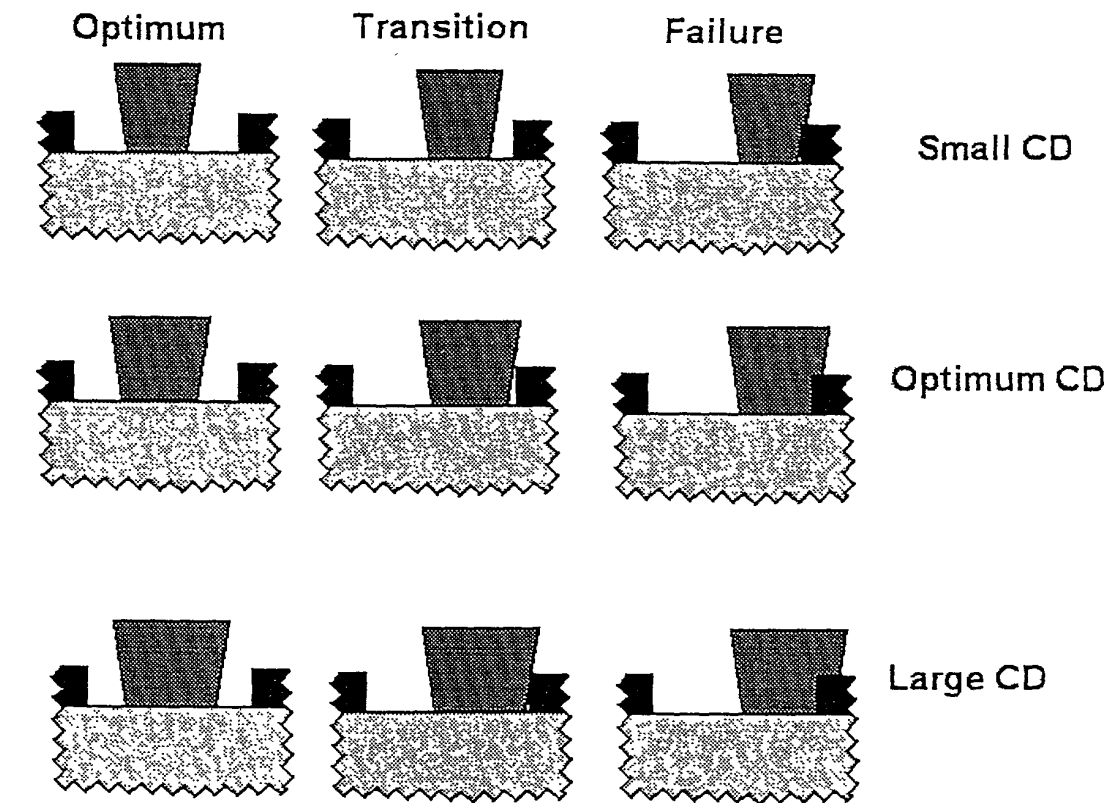
```
Exposing wafers at different
critical dimensions
```
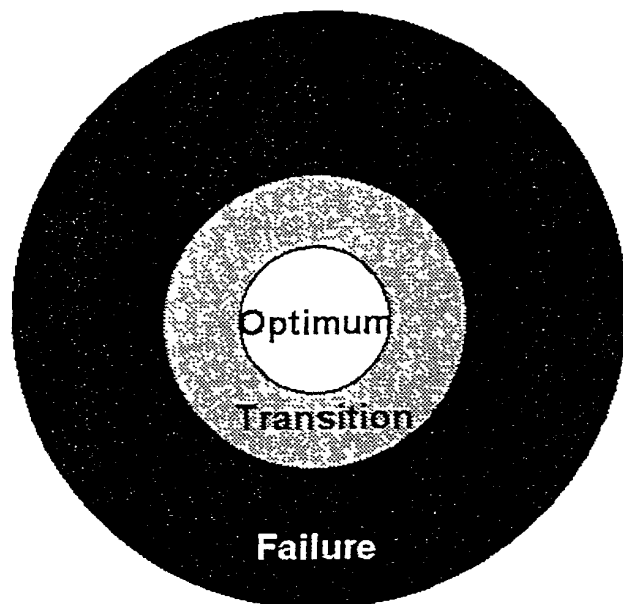
```
Varying the overlay across
each wafer
```

```
Using functional yield data to
determine the overlay
tolerance for each of the
image sizes
```

Figure 2

Figure 3